



## Contribution of X-ray Fluorescence Techniques in Cultural Heritage Materials Characterisation

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Deadline for manuscript  
submissions:

**closed (31 October 2021)**

### Message from the Guest Editors

This Special Issue is intended to collect papers dealing with any of the analytical techniques related to XRF spectroscopy appropriate for applications to Cultural Heritage materials. Paper subjects can range from instrumentation and technical developments to case studies requiring methodological innovations, from theoretical simulations to new data handling. All the variations of XRF spectroscopy will be considered: portable or mapping spectrometers, synchrotron based XRF, total reflection or grazing techniques, and synergical association with any other non-destructive analytical techniques.

### Keywords

- XRF
- pXRF
- Micro XRF
- XRF mapping
- Synchrotron based XRF
- Cultural heritage materials
- Archaeometry





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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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